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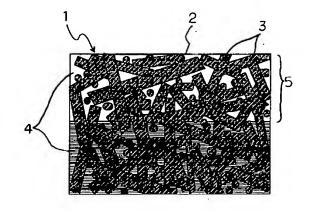
(21)出願番号	特願平10-79780	(71)出顧人	000006633		
(22)出顧日	平成10年(1998) 3月26日	(72)発明者	京セラ株式会社 京都府京都市伏見区竹田鳥羽殿町 6 番地 吉田 真		
		(10/)L91H	鹿児島県国分市山下町1番4号 京セラ株 マ会社総合研究所内		

(54) 【発明の名称】 窒化珪素質耐食性部材及びその製造方法

(57)【要約】

【課題】耐熱性に優れた窒化珪素質焼結体からなり、パーティクルの発生を抑制し得る窒化珪素質耐食性部材と その製造方法を提供する。

【解決手段】陽イオン不純物が0.5重量%以下の窒化 珪素原料粉末に対して、少なくとも0.5重量%以上の 希土類元素酸化物を添加混合した混合物を所定形状に成 形、焼成して作製された相対密度98%以上の窒化珪素 質焼結体の少なくとも塩素系腐食ガス或いはそのプラズマに晒される面を塩素および/または水素を含むガス雰 囲気で、800~1900℃で熱処理して粒界相を除去し、接触表面から10μm以上の深さにわたり、少なくとも焼結助剤及び不純物を含む粒界相が、表面から1mmの深さ位置における粒界相に対して面積比率で3分の1以下に除去した粒界相除去層を形成する。



ATTORNEY-CLIENT PRIVILEGED COMMUNICATION

Tom,

Here is one of several data summaries from Japanes patent applications.

(21)Application number: 10079780

(71)Applicant:

KYOCERA CORP

(22)Date of filing: 26.03.1998

(72)Inventor:

YOSHIDA MAKOTO

(54) SILICON NITRIDE CORROSION RESISTANT MEMBER AND ITS PRODUCTION

(57) Abstract:

PROBLEM TO BE SOLVED: To obtain a silicon nitride corrosion resistant member consisting of silicon nitride sintered body excellent in heat resistance and capable of inhibiting the generation of particles, and further to provide a production method thereof.

SOLUTION: This silicon nitride corrosion resistant member is obtained by compacting a mixture obtained by adding at least 0.5 wt.% rare earth oxide to a silicon nitride raw material powder containing 0.5 wt.% cationic impurity, and mixing the raw material powder with the added rare earth oxide to form a prescribed shape, firing the obtained compact to provide a silicon nitride sintered body 1 having 98% relative density, heat-treating at least a face to be exposed to chlorine-based corrosive gas or a plasma, of the silicon nitride sintered body 1 in an atmosphere containing chlorine and/or hydrogen at 800-1,900°C to remove a grain boundary phase and to form a boundary phase-removed layer 5 regulated so that the boundary phase 4 containing at least a sintering adjuvant and an impurity over the depth of 10 m from the contacting surface 2 may be removed so as to be 1/3 times as much as that of the boundary phase at the depth of 1 mm from the surface expressed in terms of a surface ratio.

Etch conditions: BCl3, 100sccm, RIE 1.8kW, 4 Pa. 240hr exposure

	Sintering Aid	Relative density	Heat Temp	treat Time	Gas	Depth etched		Particle count per 8"wafer	
試料 No.	残部は	密度	∄選度	M処理 時間 (hr)	雰囲 気	粒界相 除去層 の厚さ (μm)	X 1 X 2	パーティクル 発生量 個/8inch ウェハー	(
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* 2	, ,,	" "	700	20	Clz	3	0.5	16800	
3	11	<i>"</i>	800	20	C12	12	0.2	800	
4	"	<i>II</i>	1000	20	C 1 2	23	0.2	600	
* 5	,,	" "	1300	5	Cla	8	0.6	8100	
6	17)	" "	1300	10	C I 2	18	0.3	700	1
7.	17 1	<i>"</i>	1300	20	Cla	30	0.1	300	
8		" "	1300	30	Cla	36	0.1	200	
. 9	11 11	, ,,	1500	20	Cla	41	0.1	200	
10	77 //	, ,,	1700	20	Cl2	56	0.1	200	
*11	Yb203 0	, 3 93.0	1300	20	H 2	51	0.0		Measurem ent not possible
12	Yb203 0.	. 7 98. 0	1300	20	H 2	20	0.2	800	
13	Yb203 2.	.0 98.5	1300	20	H 2	26	0.3	900.	
14	Yb203 8.	0 98.7	1300	20	H 2	23	0.1	600	
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17	" "	Л	1300	20	H 2	36	0.1	600	
18	11 11	"	1700	20	H ₂	. 82	0.1	300	

Measurem ent not

*印は本発明の範囲外の試料を示す。 Table 1. Response to BCl3 plasma

99.0

2000

20

 Cl_2

150

0.0

測定不可

* 19

Yb203 7.0